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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Technology Center 2100

Applicants: Praveen PARVATHALA et al.

Serial No.: 09/917,661

Filed: July 31, 2001

**For: FUNCTIONAL RANDOM INSTRUCTION TESTING (FRIT)
METHOD FOR COMPLEX DEVICES SUCH AS
MICROPROCESSORS**

Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
Washington, DC 20231

August 30, 2001

Sir:

Entry of the following Preliminary Amendments to the above-identified application is respectfully requested.

09/04/2001 BABRAHA1 00000005 09917661

01 FC:103
02 FC:102

144.00 OP
80.00 OP

IN THE CLAIMS

Please amend claims 1-2, 4, 6, 8, 11, 12, 14, 16, 18, 21, 22, 24, 26, and 28, and claims 31-38, as follows:

1 1. (Amended) A functional random instruction testing (FRIT) method for testing a
2 complex device, comprising:
3 converting FRIT kernel into kernel test patterns and storing the kernel test patterns in a
4 tester memory;